Special Issue

Computer Vision and Pattern Recognition in the Era of Deep Learning

Message from the Guest Editor

Recently, an especially popular field of deep learning applications has been that of computer vision and pattern recognition. Typical examples of areas where deep networks have been used are object detection, face detection and recognition, optical character recognition, and image classification. In this Special Issue, we welcome contributions from scholars in all related subjects, presenting either a deep learning solution to a novel application, or a deep learning enhancement to a preexisting application.

Guest Editor

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Deadline for manuscript submissions

closed (31 December 2019)

Applied Sciences

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CiteScore 5.3

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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